

33773M064

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Toshiharu Daii, et al.

U.S. Serial No.: 10/774,529

Group Art Unit: To Be Assigned

Filed: : February 10, 2004

Examiner: To Be Assigned

For:

SEMICONDUCTOR WAFER PROCESSING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the duty of disclosure under 37 C.F.R. 1.56, Applicants are enclosing an Information Disclosure Citation Form (PTO-1449) and a copy of the cited document. The document was cited and discussed on page 2 of the Applicants' specification.

It is respectfully requested that the cited document be considered by the Examiner in the above-identified patent application and that the cited document be made officially of record therein. It is further requested that a listing of the same appear on the face of any patent which may issue from this application.

This Information Disclosure Statement is being filed within three (3) months of the filing date of the application. Therefore, it is believed that no fees are due under 37 C.F.R. Section 1.97(b)(3).

Respectfully submitted, SMITH, GAMBRELL & RUSSELL, LLP

By:

Michael A. Makuch, Reg. No. 32,263

1850 M Street, N.W., Suite 800

Washington, D.C. 20036 Telephone: (202) 263-4300

Fax: (202) 263-4329

March 2, 2004

1

1.



FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT					ATTY DOCKET 33773M064		SERIAL NO. 10/774,529		
R 0 2 2004				ě	FILING DATE February 10, 2004		GROUP ART UNIT To Be Assigned		
U.S. PATEN Examiner's DOCUMENT DATE					L				-
Examiner's		DOCUMENT	U.S. PATEN	T DOCL	NAME	CLASS	SUB-	FILING	DATE
Initials		NUMBER	DATE		IAVIAIT	CLASS	CLASS	IF APPRO	PRIATE
	AA								
	AB								
	AC		· S - 27 27 27						
	AD								
	AE								
	AF								
	AG								
			FOREIGN PAT	ENT DO	CUMENTS				
*Examiner's Initials		DOCUMENT DATE NUMBER			COUNTRY CLASS		SUB- TRANSLATION CLASS YES NO		
	AH	2001-257248	9/21/01		Japan		CLASS	123	X
	Al								
	AJ								
	AK								
	<u></u>								
	AL	THER INFORM	ATION (Including a	Author, I	itle, Date, Pertir	ent Pages, I	±tc.)		
	AM								
	AN			-		<u> </u>			
	AO								
	AP								
	AQ						 .		
	AR		-						
EXAMINER:				DA	TE CONSIDERED):			
				1					
'EXAMINER:	Initial if	f reference consider	ed, whether or not ci	tation is in	conformance wit	h MPEP 609	Draw line	through cita	ation if
not in conform	anco a	nd not considered.	In almaha a a a a a Alaia	C			_	-	